



Kompetenzzentrum
Ultrapräzise
Oberflächen-
bearbeitung e.V.

Please fax your registration to: +49 (0) 531 - 592 - 695131

- ☐ I am interested in this meeting. Please send me more information.
☐ I hereby register for the Asphere Metrology Workshop.
☐ I plan to take part in the evening "get together" on December 8th.

Firm, Institution: _____

Title, Family Name: _____

First Name: _____

Address: _____

Postal Code, City: _____

Tel., Fax: _____

E-mail: _____

Signature: _____

click here to register:

http://www.upob.de/index.php?option=com_phocadownload&view=category&id=23:workshop-asphere-metrology-2010&download=69:online-registration-workshop-asphere-metrology-2010&Itemid=70

Attendance may be cancelled by the participant up to 14 days before the meeting starts at 50 % of the attendance fee. Following that date or if the participant does not attend the meeting, we will charge the full amount. Cancellations must be made in writing. We would be glad to accept another participant as attendance fees are transferable.

Organizational Details

Date:

December 9th 2010

Location:

PTB Braunschweig;
Meitner Laboratory Building
Directions: www.upob.de/ → Kontakt

Language:

English

Accommodation:

Recommended accommodation
www.upob.de/ → Veranstaltungen
→ Workshop

Registration:

Registration deadline:
November 30th 2010

Please register by letter or fax using the attached form. Following this, you will receive confirmation.

Attendance Fee:

Lecturers: no fees (1st person)
Member: € 50
Non-member: € 150
Payment in advance or in cash at the registration desk.

Contact:

CC UPOB e. V.
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Workshop

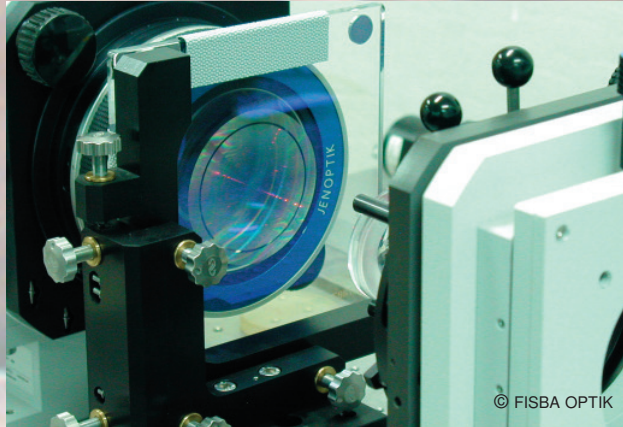
December 9th 2010



**7th Workshop
"Asphere Metrology"**



**2010
Workshop**



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7th Workshop 2010

Aspheres - whether as an aid for poor eyesight, in mobile phones or large optics - are in use all around us. As widespread as their applications are, it is still difficult to produce or to measure them. This is revealed by current practice, where large measurement uncertainties sometimes emerge.

Unsatisfactory quality or the bad repeatability of measurement results have already been known for quite a long time. However, experts are still searching for the best way to improve this situation and to provide reliable results.

There was a meeting in spring 2010, where experts came together in order to face these problems and to discuss the manifold options for measuring and comparing aspherical surfaces. During the follow-up workshop, which is going to be held in December 2010, additional institutions will present their results and measurements on the investigated reference aspheres. Theoretical contributions on topics like standardization and the characterization of aspheres will complete the programme of the workshop.

Would you like to attend this interesting dialogue?
Then please log in!

**December 9th 2010
at PTB, Braunschweig**

Background

Joint Investigation

Two selected aspheres were investigated by a number of companies and institutes. Theoretical papers detail asphere metrology and standardization.

During the workshop these institutions will take an active part:



Agenda

Wednesday, December 8th / Evening

18.30 Get Together / Restaurant Al Duomo

Thursday, December 9th

Morning

Chairman: M. Schulz; PTB; Germany

8.30 Opening

F. Löffler; CC UPOB e.V.; Germany

8.45 Overview / Summary Measurements Last HLEM - The Story So Far

K.F. Beckstette; Carl Zeiss Jena GmbH; Germany

9.30 Measurement of Aspheres and Freeform Surfaces with the Tilted-wave Interferometer

E. Garbusi; ITO University Stuttgart; Germany

10.15 Coffee Break

10.45 Standardization in Precision Optics

E. Leitner; DIN Deutsches Institut für Normung e.V.; Germany

11.30 New Measurements of Aspherical Surfaces Using 3D-deflectometry

Mahns; TRIOPTICS GmbH; Germany

12.15 Lunch Break

Afternoon

Chairman: J.-M. Asfour; Dioptric GmbH; Germany

13.30 Asphere and Freeform Surface Measurements with the NANOMEFOS Non-contact Measurement Machine

R. Henselmans / G. Gubbels; TNO Science & Industry; Netherlands

14.15 Orthogonality Enables the Characterization of Increasingly Complex Aspheres

P. Murphy / J. P. Lormeau; QED Technologies Inc.; USA

15.00 Coffee Break

15.20 Final Discussion

J.-M. Asfour; Dioptric GmbH; Germany

16.20 Closing of Workshop

16.30 End